

Using internal current excitation and built in voltage reference

$V_{REF} = 2.048 \text{ V}$; 5ppm/°C drift; Long term drift 1000h = 110ppm

$I_{DAC} = 100\mu\text{A}$; 50 ppm/°C drift

$R_{RTD(37^\circ\text{C})} = 1143.9\Omega$, resistance of PT1000 on 37.00°C

$$V_{ADC} = V_{REF} \frac{\text{CODE}}{2^n}, \text{ ADC conversion formula}$$

$$V_{ADC} = R_{RTD} * I_{REF}$$

$$R_{RTD} * I_{DAC} = V_{REF} \frac{\text{CODE}}{2^n}$$

$$R_{RTD} = \frac{V_{REF}}{I_{DAC}} * \frac{\text{CODE}}{2^n}$$

If we analyze scenario where PT1000 temperature remains the same (37.00°C) but ambient temperature where electronics is located rises +20°C then $V_{REF+20^\circ\text{C}}$ and $I_{DAC+20^\circ\text{C}}$ because of temperature drift will be:

$$V_{REF+20^\circ\text{C}} = V_{REF} \pm V_{REF} * 5\text{ppm} * 20 = V_{REF} \pm V_{REF} * 0.0001 = V_{REF}(1 \pm 0.0001)$$

$$I_{DAC+20^\circ\text{C}} = I_{DAC} \pm I_{DAC} * 50\text{ppm} * 20 = I_{DAC} \pm I_{DAC} * 0.001 = I_{DAC}(1 \pm 0.001)$$

Measured code at ambient temperature +20°C will be:

$$\text{CODE}_{+20^\circ\text{C}} = \frac{V_{ADC} * 2^n}{V_{REF+20^\circ\text{C}}} = \frac{I_{DAC+20^\circ\text{C}} * R_{RTD(37^\circ\text{C})} * 2^n}{V_{REF+20^\circ\text{C}}}$$

Because we don't know the ambient temperature and during calculation we will consider standard values of I_{DAC} and V_{REF} calculated $R_{RTD+20^\circ\text{C}}$ on rised ambient electronics temperature of +20°C will be:

$$R_{RTD+20^\circ\text{C}} = \frac{V_{REF}}{I_{DAC}} * \frac{\text{CODE}_{+20^\circ\text{C}}}{2^n} = \frac{V_{REF}}{I_{DAC}} * \frac{I_{DAC+20^\circ\text{C}} * R_{RTD(37^\circ\text{C})} * 2^n}{V_{REF+20^\circ\text{C}} * 2^n}$$

If we calculate extreme condition where $I_{DAC+20^\circ\text{C}} = I_{DAC}(1 + 0.001)$ and $V_{REF+20^\circ\text{C}} = V_{REF}(1 - 0.0001)$

$$R_{RTD+20^\circ\text{C}} = \frac{V_{REF}}{I_{DAC}} * \frac{I_{DAC}(1 + 0.001) * R_{RTD(37^\circ\text{C})} * 2^n}{V_{REF}(1 - 0.0001) * 2^n} = R_{RTD(37^\circ\text{C})} \frac{1.001}{0.9999} = 1145.16$$

Which gives us measured temperature of 37.33°C which is error of +0.33°C

Using ratiometric measurement

R_{REF} with temperature drift of $\pm 5ppm$ and long term drift 0.04% 10 000h at 70°C

$$R_{RTD} = R_{REF} * \frac{CODE}{2^n}$$

If we analyze same scenario where PT1000 temperature remains the same (37.00°C) but ambient temperature where electronics is located rises +20°C then R_{REF} because of temperature drift will be:

$$R_{REF+20^\circ C} = R_{REF} \pm R_{REF} * 5ppm * 20 = R_{REF}(1 \pm 0.0001)$$

Measured code will be

$$CODE_{+20^\circ C} = \frac{R_{RTD} * 2^n}{R_{REF+20^\circ C}}$$

Because we don't know the ambient temperature and during calculation we will consider standard values of R_{REF} , calculated $R_{RTD+20^\circ C}$ on rised ambient electronics temperature of +20°C will be:

$$\begin{aligned} R_{RTD+20^\circ C} &= R_{REF} * \frac{CODE_{+20^\circ C}}{2^n} = R_{RTD} * \frac{R_{REF}}{R_{REF+20^\circ C}} = R_{RTD} * \frac{R_{REF}}{R_{REF}(1 \pm 0.0001)} \\ &= R_{RTD} \frac{1}{1 \pm 0.0001} \end{aligned}$$

$$R_{RTD+20^\circ C} = 1143.79\Omega$$

Which gives us measured temperature of 36.97°C which is error of +0.03°C which is 10 times lower error than previous measurement
